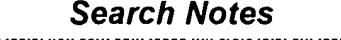


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/073,495	STEVENS, ET AL.
	Examiner	Art Unit
	Tse Chen	2116

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner